

# ELECTRONIC DEVICES NOTES

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## Electronic Devices Notes, First Edition

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# Semiconductors

## Semiconductors

- ↳ Conductivity varies with Temp., optical excit<sup>n</sup> & impurity content
- ↳ used for electronic & optoelectronic  $f^ns$  because of its variety of electronic & optical properties.

## Silicon better than Germanium

- ↳ Stable, ~~is~~ strong material, crystal structure like diamond.
- ↳ less noisy (output isn't linear  $\rightarrow$  variations come)
- ↳ Higher operating temp (125-175 °C)
- ↳ Ge breaks above 90 °C
- ↳ Easily available

## Compounds semiconductors (doped)

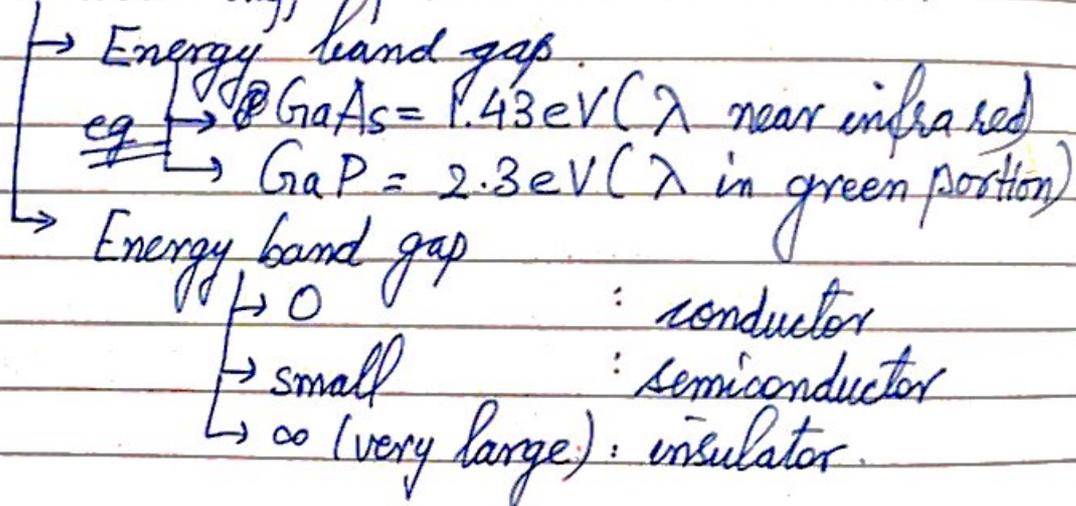
- ↳ used for high-speed devices
- ↳ devices requiring emission & absorption of light.

☐ 4f ☐

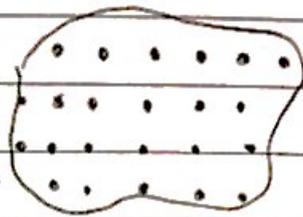
- ↳ 2 elemts : BINARY (GaN,
- ↳ 3 elemts : TERNARY
- ↳ 4 elemts : QUATERNARY

- \* ZnS semiconductor : used for fluorescent materials
- \* InSb, CdSe or PbTe & HgCdTe : Light detectors
- \* Si & Ge : Infrared & nuclear radiation detectors
- \* GaAs or InP : Microwave devices like Gunn Diode  
produce high  $\gamma$  oscillations
- \* GaAs, AlGaAs & other ternary & quaternary  
comps : Semiconductor lasers

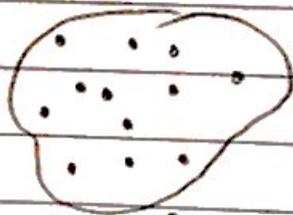
\* Semiconductor diff<sup>t</sup> from metal & insulator



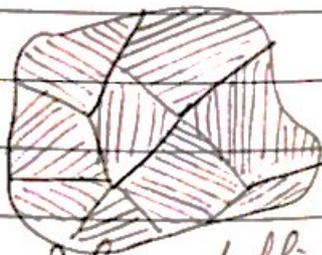
\* Polycrystalline solids : have many small regions of crystalline materials



Crystalline



Amorphous



Polycrystalline

- \* Lattice : Periodic Array of pts. in space.
- \* Basis : Atoms or groups of atoms in each lattice pt.
- Crystal structure = Lattice + Basis.
- \* Unit cell : Smallest volume that repeats itself throughout the crystal.

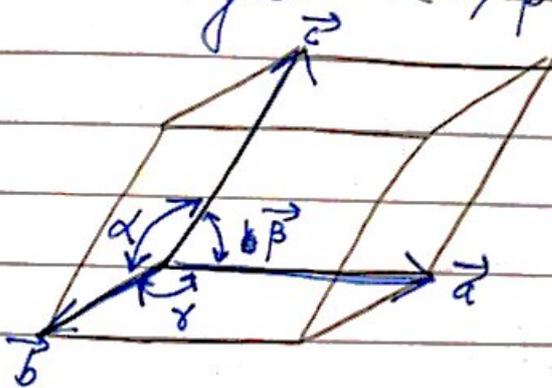
\* A primitive cell has lattice pts. only in the corners. <sup>hence,</sup> effective no. of lattice pts. is always UNITY ( $\because$  one lattice pt. can make vector connecting other lattice pts. to make a unit cell)

\* 3D lattices can be generated with 3 basis vectors.

\* Unit cell of a general 3D lattice is described by 6 nos. (need not be independent):

▷ 3 distances ( $a, b, c$ )

▷ 3 angles ( $\alpha, \beta, \gamma$ )



### CUBIC LATTICE

Simple cubic (SC)

Face Centered (FCC)

Body Centered (BCC)

\* Calcul<sup>n</sup> of nearest neighbour distance  
=  $\frac{1}{2}$  of diagonal of a face

$$= \frac{1}{2} (a\sqrt{2})$$

$$= \frac{1}{2} [4 \times (\text{Radius of atom})]$$

★ BCC : Nearest neighbour distance

$$= \frac{1}{2} \times (\text{Diagonal of a cube})$$

$$= \frac{1}{2} \times (\sqrt{3} a)$$

$$= \frac{1}{2} \times (4 \times \text{Radius of atom})$$

- ★ Semiconductors are having Diamond structure.
- ↳ FCC structure
  - ↳ One extra atom at  $\frac{a}{4} + \frac{b}{4} + \frac{c}{4}$  from each FCC atom
  - ↳ eg: GaAs (Zinc Blende)

## ★ PLANES & DIR<sup>NS</sup>

★ The planes are known as Miller Indices, denoted by  $(h \ k \ l)$

↳ To find a plane:

1. Find intercepts of the plane along 3 axis in integral multiple of basis vectors.
  2. Take reciprocal of intercepts.
  3. Reduce to smallest set of integers.
  4. Label the plane  $(h \ k \ l)$ .
- for indices with  $\parallel$  to plane. Intercept =  $\infty$ . So, reciprocal gives 0.

\* Dir<sup>n</sup> in a lattice is expressed as a set of 3  $\mathbb{Z}$  [p q r] being the components of a vector in that dir<sup>n</sup>.

The 3 vector components are expressed in multiples of basis vectors, reduced to the smallest values with the same rel<sup>n</sup>ship.

## \* INTERPLANAR DISTANCE

Distance b/w adjacent planes is  $d$  or  $d_{hkl}$  is the interplanar distance.

ONLY in a cubic sys, dir<sup>n</sup> indices of a dir<sup>n</sup>  $\perp$  to a crystal plane are the same as its Miller Indices.

Calculate interplanar distance

$$d = d_{hkl} = \frac{a}{\sqrt{h^2 + k^2 + l^2}}$$

\* Angle  $\theta$  b/w 2 diff<sup>t</sup> miller indices (planes)

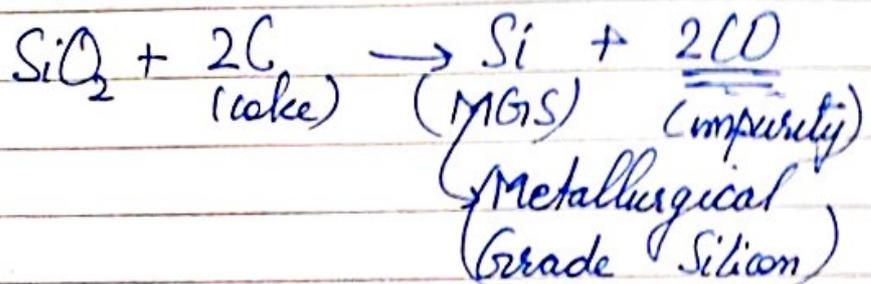
$$\cos \theta = \frac{h_1 h_2 + k_1 k_2 + l_1 l_2}{\sqrt{h_1^2 + k_1^2 + l_1^2} \sqrt{h_2^2 + k_2^2 + l_2^2}}$$

$$\sqrt{h_1^2 + k_1^2 + l_1^2} \sqrt{h_2^2 + k_2^2 + l_2^2}$$

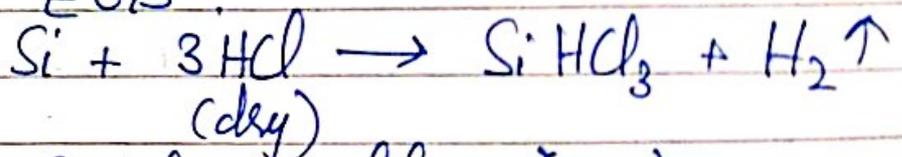
\* EGS : Electronic Grade Silicon.

\* BULK ~~CRYSTAL~~ CRYSTAL GROWTH.

• Starting material ( $\text{SiO}_2$ )

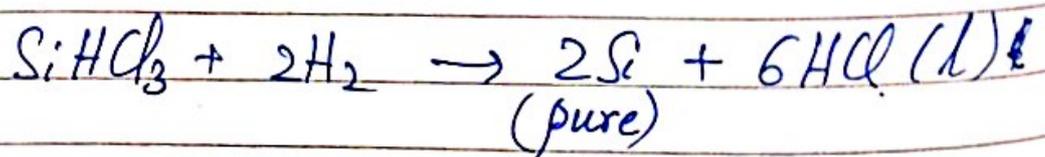


• Impurity reduced to 1 ppb (parts per billion) to get EGS.



• Extract  $\text{SiHCl}_3$  (trichlorosilane)

•  $\text{SiHCl}_3$  is converted to EGS or semiconductor grade Si  $\rightarrow$  React with  $\text{H}_2$ .



\* Polycrystalliz<sup>n</sup> method of Si

$\rightarrow$  Czochralski Method.

$\rightarrow$  Melted & held in Quartz.

$\rightarrow$  Seed crystal put & taken out slowly, by rotating.

$\rightarrow$  Si, Ge, GaAs are grown by this method.

\* LEC Growth (Liquid Encapsulated Czochralski)  
For volatile elements, layer of  $B_2O_3$  is floated on the surface of the melt to prevent evaporation.

\* DOPING

Done at solidifying interface b/w melt & solid.

$$\text{Distribution coeff (} k_d) = \frac{C_s}{C_l}$$

→ conc. of impurity in solid

→ conc. of impurity in liquid

ex. for a BCC lattice of identical atoms with a lattice constant of 5 Å, calculate the max packing fraction and the radius of the atoms treated as hard spheres with the nearest neighbours touching.

Nearest atoms are at a distance =  $\frac{\sqrt{3}}{2} \times 5 \times 10^{-10} \text{ m}$

$= 4.33 \text{ \AA}$

Radius of atoms =  $\frac{1}{2} \times$  Nearest neighbour distance

$$r = \frac{1}{2} \times (4.33 \text{ \AA})$$

Volume of each atom =  $\frac{4}{3} \pi r^3 = 42.5$

No. of atoms per cube =  $1 + \left(8 \times \frac{1}{8}\right) = 2$

Packing fraction ( $\phi$ ) =  $\frac{\text{Volume of each atom} \times \text{No. of atoms}}{\text{Volume of cube}}$

\* If Miller Indices = 0  $\Rightarrow$  It's  $\perp$  to other 2 axes  
 $\because \frac{1}{0} = \infty \Rightarrow \perp$  to that axis

Q Calculate %age of free space ( $100 - \phi$ ) in FCC

$$\text{radius}^{(r)} = \frac{1}{2} (a\sqrt{2}) = \frac{a}{\sqrt{2}}$$

$$\begin{aligned} \text{Volume of each atom} &= \frac{4}{3} \pi r^3 = \frac{24}{3} \pi \frac{(a^3)}{2\sqrt{2}} \\ &= \frac{2}{3\sqrt{2}} \pi a^3 \end{aligned}$$

$$\text{No. of atoms} = \left(8 \times \frac{1}{8}\right) + 6\left(\frac{1}{2}\right) = 4$$

$$\phi = \frac{\sqrt{2}}{3} \pi a^3 \times 4$$

$$\phi = \frac{4\sqrt{2}}{3} \pi a^3 = 5.92$$

Q Calculate miller indices of plane shown

	X	Y	Z
Intercepts	$\frac{2}{3}$	-1	$\frac{1}{2}$
Reciprocal	$\frac{3}{2}$	-1	2
Reduction	3	-2	4
Miller Indices	(3	2	4)

Q. Calculate of volume density of Si atoms (no. of atoms/cm<sup>3</sup>) given that lattice constant of Si is 5.43 Å. Calculate areal density of atoms (number/cm<sup>2</sup>) on (100) plane  
 DIAMOND structure of Si  $\rightarrow$  FCC  
 + 4 atoms completely inside cubic cell  
 $= 4 + 8\left(\frac{1}{8}\right) + 6\left(\frac{1}{2}\right) = 8$  atoms

$$\text{Volume of cell} = (5.43 \text{ \AA})^3 = 1.6 \times 10^{-22} \text{ cm}^3$$

$$\text{Density} = \frac{8}{\text{cm}^3} = \frac{8}{1.6 \times 10^{-22}} = 5 \times 10^{22} \text{ atoms/cm}^3$$

$$\text{In (100) plane} = \left(4 \times \frac{1}{4}\right) + \left(\frac{1}{2} \times \frac{1}{2}\right) = 2 \text{ atoms}$$

$$= \frac{2}{(5.43 \text{ \AA})^2} = 6.8 \times 10^{14} \text{ cm}^{-2}$$

Q. A Si crystal is to be grown by the Czochralski method & it is desired that the ingot contain  $10^{16}$  phosphorous atoms/cm<sup>3</sup>.

(a) What conc. of phosphorous atoms should the melt contain to give this impurity concentration in the crystal during the initial growth? For P in Si,  $k_d = 0.35$

(b) If the initial load of Si in the crucible is 5 kg, how many grams of P should be added. Atomic weight of P = 31.

$$(a) k_d = \frac{C_s}{C_l} \Rightarrow C_l = \frac{10^{16}}{0.35} \text{ atoms}$$

(b)

## \* EPITAXIAL GROWTH or EPITAXY

Methods  
 Chemical vapor deposition (CVD) Molecular beam Epitaxy ~~SAD~~ ?

\* Heteroepitaxy : In case of Epitaxial layer mismatch.

\* Any compd (mono, binary, ternary or quaternary) compd can be grown over the other : provided their lattice const. match.

\* If  $\exists$  a mismatch in lattice const., we can change lattice const. during Epitaxial growth.

\* Pseudomorphic : If  $\exists$  little mismatch, compression or tension would be there. Thin layers grown.

\* Misfit disloc<sup>ns</sup> : If layer exceeds critical thickness.

\* SLS : Strained-layer.

# Ph: ELEMENTARY

## QUANTUM MECHANICS

developed by Heisenberg & Schrodinger

- Quantum particles can act both as particles & waves  
 WAVE-PARTICLE duality
- Quantum mechanics uses Probability theory

\* Heisenberg's Uncertainty Principle.

$$(\Delta x)(\Delta p) \geq \frac{\hbar}{2} ; (\Delta x)(\Delta p) \geq \frac{h}{4\pi}$$

∴ ∃ uncertainty in energy & time

$$(\Delta E)(\Delta t) \geq \frac{\hbar}{2} ; h = 6.625 \times 10^{-34} \text{ Js}$$

$$\hbar = \frac{h}{2\pi}$$

\* In 1D: probability of finding the particle in range  $x$  to  $(x+dx)$  is  $P(x) dx$

\*  $P(\text{particle is somewhere in the entire space})$

$$\int_{-\infty}^{\infty} P(x) dx = 1$$

\*  $\Psi$  = Probability density (a wavefunction)  
 $|\Psi|^2$  = Probability.

Postulate ①

\* Each particle in a physical sys. is described by a wavefn  $\Psi(x, y, z, t)$ .

&

$\nabla \Psi$  should be

$\left\{ \begin{array}{l} \rightarrow \text{finite} \\ \rightarrow \text{single valued} \\ \rightarrow \text{cts.} \end{array} \right.$

\* BASIC POSTULATES

Postulate ②

Classic variable

$x$

$f(x)$

momentum,  $p(x)$

$E$

Quantum operator

$x$

$f(x)$

$\frac{\hbar}{j} \frac{\partial}{\partial x}$

$-\frac{\hbar}{j} \frac{\partial}{\partial t}$

$;\hbar = \frac{h}{2\pi}, j: \text{complex const.}$

Postulate ③

\* Probability of finding a particle with wavefn  $\Psi$  in volume  $dx dy dz$  is  $\Psi^* \Psi dx dy dz$ .

Normaliz<sup>n</sup> cond<sup>n</sup> of wavefn :-

$$\int_{-\infty}^{\infty} \Psi^* \Psi dx dy dz = 1$$

\* We can find only avg. values of these physical quantities.

These avg. values, called EXPECTATION VALUES  
 are found as an operator  $\hat{Q}_{op}$  is.

$$\int_{-\infty}^{\infty} \hat{Q}_{op} \Psi^* \Psi \, dx \, dy \, dz.$$

### \* SCHROEDINGER EQ<sup>n</sup>

KE + PE = Total energy i.e.  $\frac{p^2}{2m} + V(x) = E$   
 (to Quantum)

2D:  $-\frac{\hbar^2}{2m} \frac{\partial^2 \Psi(x,t)}{\partial x^2} + V(x) \Psi(x,t) = -\frac{\hbar}{j} \frac{\partial \Psi(x,t)}{\partial t}$

3D:  $-\frac{\hbar^2}{2m} \nabla^2 \Psi + V \Psi = -\frac{\hbar}{j} \frac{\partial \Psi}{\partial t}$

$$\Psi_{(x,t)} = \psi_{(x)} \phi(t)$$

$$\hookrightarrow -\frac{\hbar^2}{2m} \frac{\partial^2 \psi_{(x)} \phi(t)}{\partial x^2} + V(x) \psi_{(x)} \phi(t)$$

$$= -\frac{\hbar}{j} \psi_{(x)} \frac{\partial \phi(t)}{\partial t}$$

separate in 2 eq<sup>ns</sup>

Time Independent

Time dependent  
 $\frac{d \phi(t)}{dt} + \frac{jE}{\hbar} \phi(t) = 0$

$$\frac{d^2 \psi(x)}{dx^2} + \frac{2m}{\hbar^2} [E - V(x)] \psi(x) = 0$$

\* For particle in a box sys,  
 $E \text{ (or } V) = 0$  ,  $0 < x < L$   
 $\rightarrow \infty$  ,  $x=0 \& x=L$

So, b/w  $0$  &  $L$ , eq<sup>n</sup> changes to

$$\frac{\partial^2 \psi(x)}{\partial x^2} + \frac{2m}{\hbar^2} E \psi(x) = 0$$

$$\Rightarrow \frac{\partial^2 \psi(x)}{\partial x^2} = - \left( \frac{2mE}{\hbar^2} \right) \psi(x)$$

$\rightarrow k$

Solving :-

$$\psi(x) = A \sin kx + B \cos kx$$

$\rightarrow x=0 \& x=L, \psi(x) = 0$

$$\Rightarrow \psi(0) = A \sin(0) + B \cos(0) = 0$$

$$\Rightarrow B = 0$$

$$\Rightarrow \psi(x) = A \sin kx$$

At  $x=L$

$$\Rightarrow \psi(L) = A \sin kL = 0$$

$$\Rightarrow kL = n\pi$$

$$\Rightarrow k = \frac{n\pi}{L} \text{ or } k_n = \frac{n\pi}{L}$$

$n \in \mathbb{Z}$

$$\text{So, } \psi(x) = A \sin \left[ \frac{n\pi}{L} x \right] ; n \in 1, 2, \dots$$

$\rightarrow$  Find  $A$  : Using normalization.

$$\int_0^L \psi^*(x) \psi(x) dx = A^2 \frac{L}{2} = 1$$

(Total Probability = 1)

$$\text{So } \psi_n(x) = \sqrt{\frac{2}{L}} \sin\left(\frac{n\pi x}{L}\right)$$

↳ Schrodinger eq<sup>n</sup> for particle well or particle in a box.

### \* TUNNELING:

When KE of particle is smaller than the potential barrier in front of it, it still has some property to penetrate through barrier.

Note: This happens only when the barrier potential is not infinite. &  $\psi \neq 0$  at barrier.



$\psi^2$  exists. So,  $\exists$  probability of existence of particle ahead of boundary.

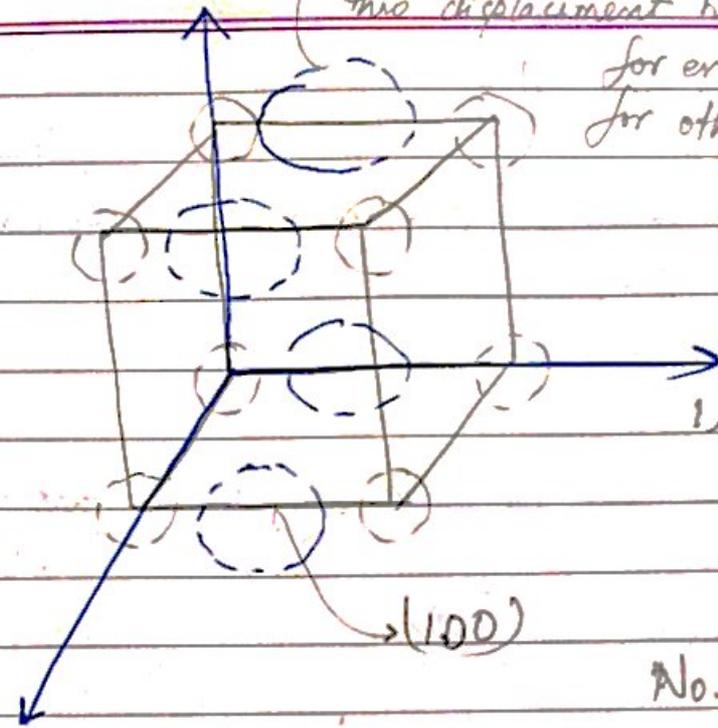
### \* SEMICONDUCTOR - QUESTIONS

Q. Sketch an SC unit cell with a lattice constant,  $a = 4 \text{ \AA}$ ; whose diatomic basis of atom A is located at lattice sites, and with atom B displaced by  $(\frac{a}{2}, 0, 0)$ . Assume that both atoms have same size and we have a closed packed structure.

Calculate:

- (i) Packing fraction.
- (ii) No. of B atoms p.u. volume.
- (iii) No. of A atoms p.u. area on (100) plane.

They are displaced by  $\frac{a}{2}$  for every side that is  $\frac{a}{2}$  for other unit cells



$a = 4R$

○ : A  
○ : B

1) Radii of A & B atom =  $1A$   
 $\left(\frac{4}{2 \times 2}\right)$

No. of A atoms =  $\frac{1}{8} \times 8 = 1$

No. of B atoms =  $\frac{1}{4} \times 4 = 1$

Volume of atoms =  $1 \times \frac{4}{3} \pi R^3 + 1 \times \frac{4}{3} \pi R^3$

$R = 1A$

$= 8.373 \times 10^{-30} \text{ unit } m^3$

(a) Packing fraction =  $\frac{\frac{8\pi}{3} \times (R)^3}{a^3} = \frac{8\pi \times (R)^3}{64 \times (R)^3}$

$= \frac{\pi}{24} = 13.083\%$

Packing fraction of

No. of B atoms ~~per vol~~ =  $\frac{\text{Vol}_B}{\text{Total vol}}$   
 $= \frac{\frac{4}{3} \pi R^3 \times 1}{a^3}$

$= \frac{14\pi}{3 \times 64} = \frac{\pi}{48} = 0.0654$

$$(ii) \frac{1}{64(A)^3} = 1.56 \times 10^{+22} / \text{cm}^3$$

$$(iii) \frac{\frac{1}{8} \times 4}{16(A)^3} = \frac{3.125 \times 10^{+14}}{7.8125 \times 10^{+14}} \text{ per cm}^3$$

A crystal with a  
 Q  $\uparrow$  SCC & a monoatomic basis has atomic radius of  
 2.5 Å & At. wt 5.42. Find  $\rho$  assuming  
 atoms touch each other.

$$r = 2.5 \text{ \AA} \quad \rho = \frac{5.42 \times 1}{\frac{4}{3} \pi r^3} = 8.285 \times 10^{22} \text{ u/cm}^3$$

5.42 is g/mol. So,  $\rho / \text{atom} = ?$   $5.42 \times N_A$   
 $= 5.42 \times 6.022 \times 10^{23}$

$$\rho = \frac{5.42 \times 6.022 \times 10^{23} \times (1)}{a^3} \text{ g/atom}$$

$$= \frac{5.42 \times 6.022 \times 10^{23}}{(2 \times 2.5)^3 \times (\text{\AA})^3}$$

$$= 2.611 \times 10^{22} \times 10^{24}$$

$$\rho = 2.611 \times 10^{46} \text{ g/atom}$$

Q A Si crystal is to be grown using Czochralski method & it is desired that ingot contains  $10^{16}$  phosphorous atoms/cm<sup>3</sup>.

(a) What conc. of P atoms should the melt contain to give this impurity conc in the crystal during initial growth? For P in Si,  $k_d = 0.35$

$$10^{16} \leftarrow \frac{C_s}{C_L} = k_d \Rightarrow C_L = 2.86 \times 10^{16}$$

(b) If initial load of Si in crucible is 5 kg, how many grams of P should be added?

P  $\rightarrow$  at. wt = 31

Ans:- Given  $\rho_{Si} = 2.33 \text{ g/cm}^3$

P is very less in Volume ( $\because$  5 kg Si)

So, can be neglected.

$$\text{(Volume)}_{\text{melt}} = \frac{m_{Si}}{\rho_{Si}} = \frac{5000}{2.33} = 2146 \text{ cm}^3 \text{ of Si}$$

& [No. of atoms = conc.  $\times$  vol.]

$$(N) = 2.86 \times 10^{16} \times 2146 = 6.14 \times 10^{19} \text{ atoms.}$$

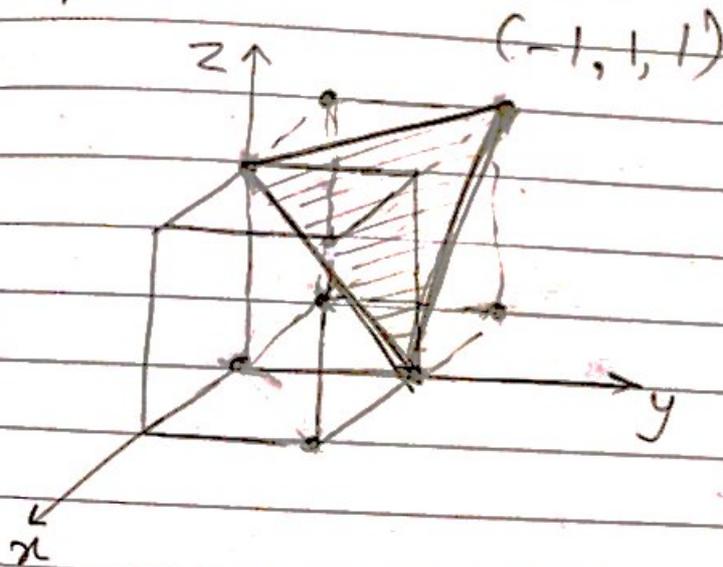
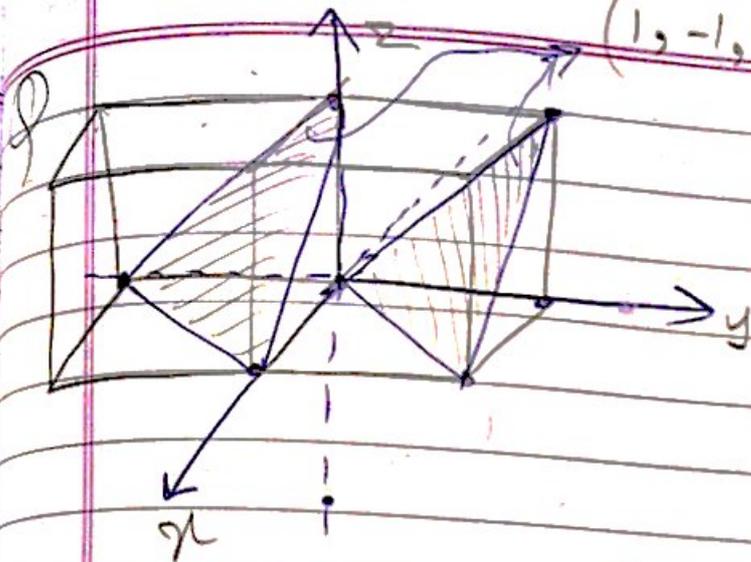
$$\text{So, amt. of P reqd} = \frac{N \times M}{N_A} = \frac{6.14 \times 10^{19} \times 31}{6.022 \times 10^{23}} = 3.16 \times 10^{-3} \text{ g}$$

# Drawing plane with Miller Indices $(1, -1, 1)$

Puffin

Date \_\_\_\_\_

Page \_\_\_\_\_



Q A Si crystal is to be pulled from the melt & doped with As ( $k_d = 0.3$ ). If Si weighs 1kg, how many grams of As should be introduced to achieve  $10^{15} \text{ cm}^{-3}$  doping during initial growth.

$$\frac{C_s}{C_L} = k_d = \frac{10^{15}}{0.3} = C_L \quad (\text{Given } \text{As} = 74.9 \text{ g/mol})$$

$$= 3.33 \times 10^{15} \quad \approx 75$$

$$\text{Volume} = \frac{1000}{2.33} = 429.184 \text{ cm}^3$$

$$\text{No. of atoms} = 3.33 \times 10^{15} \times 429.184 \text{ atoms}$$

$$\text{amt. of As} = \frac{3.33 \times 10^{15} \times 429.184 \times 75}{6.022 \times 10^{23}} = 1.78 \times 10^{-4} \text{ g}$$